



BYD Microelectronics Co., Ltd

BF9024SPD-M

P-Channel MOSFET and Schottky Diode

General Description

The BF9024SPD-M uses advanced trench technology to

Provide excellent $R_{DS(on)}$ and low gate charge.

This device is suitable for used as a load switch or in PWM applications.

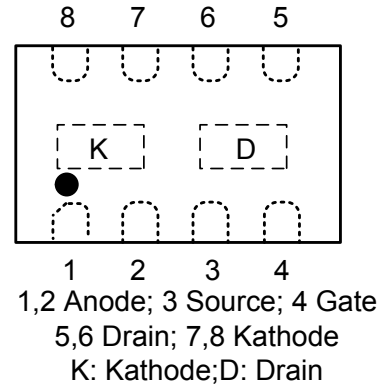
Features

MOSFET

- $V_{DS} (V) = -20V$
- $I_D = -2.7A$
- Low on-state resistance
 $R_{DS(on)} < 90m\Omega . (V_{GS} = -4.5V)$
 $R_{DS(on)} < 120m\Omega . (V_{GS} = -2.5V)$

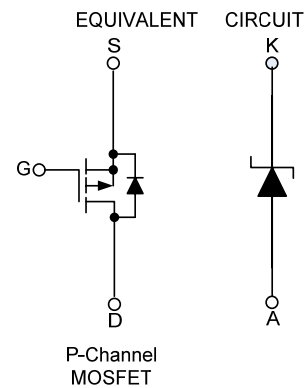
Schottky Diode

- $V_F=0.42V$



Absolute Maximum Ratings (Ta = 25°C)

Parameter	Symbol	Ratings	Unit
Mosfet			
Drain to Source Voltage (MOSFET and Schottky)	V_{DSS}	-20	V
Gate to Source Voltage	V_{GSS}	± 8	V
Drain Current (DC)	$I_{D(DC)}$	-2.7	A
Drain Current (pulse)	$I_{D(pulse)}$	-10	A
Maximun Power Dissipation ^a	P_D	1.1	W
Channel Temperature	T_{ch}	150	°C
Storage Temperature	T_{stg}	-55~+150	°C
Schottky Diode			
Reverse Voltage	V_{KA}	20	V
Average Forward Current	I_F	1	A
Pulsed Forward Current	I_{FM}	7	A
Maximun Power Dissipation ^a	P_D	0.96	W
Storage Temperature	T_{stg}	-55~+150	°C



Note a. Mounted on FR4 Board of 1"x1".

Caution: These values must not be exceeded under any conditions.

Ordering Information

- BF9024SPD-M
- DFNWB3*1.8-8L

Electrical Characteristics ($T_C = 25^\circ\text{C}$)

Characteristic	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Mosfet						
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -20V, V_{GS} = 0V$	—	—	-1	μA
Gate Leakage Current	I_{GSS}	$V_{GS} = \pm 8V, V_{DS} = 0V$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = -0.25\text{mA}$	-0.45	—	-1	V
Forward Transfer Admittance	$ y_{fs} $	$V_{DS} = -10V, I_D = -2A$	—	7	—	S
Drain to Source On-state Resistance	$R_{DS(on)}$	$V_{GS} = -4.5V, I_D = -2A$	—	73	90	$\text{m}\Omega$
		$V_{GS} = -2.5V, I_D = -2A$	—	99	120	$\text{m}\Omega$
Input Capacitance	C_{iss}	$V_{DS} = -10V, V_{GS} = 0, f = 1\text{MHz}$	—	427	—	pF
Output Capacitance	C_{oss}		—	72	—	pF
Reverse Transfer Capacitance	C_{rss}		—	50	—	pF
Turn-on Delay Time	$t_{d(on)}$	$V_{DS} = -10V,$ $I_D = -1A,$ $V_{GS} = -4.5V,$ $R_G = 6\Omega$	—	15	—	ns
Rise Time	t_r		—	36	—	ns
Turn-off Delay Time	$t_{d(off)}$		—	36	—	ns
Fall Time	t_f		—	30	—	ns
Total Gate Charge	Q_G	$V_{DS} = -10V,$ $V_{GS} = -4.5V,$ $I_D = -2A$	—	5	—	nC
Gate to Source Charge	Q_{GS}		—	1.5	—	nC
Gate to Drain Charge	Q_{GD}		—	1	—	nC
Body Diode Forward Voltage	$V_{F(S-D)}$	$I_F = -0.9A, V_{GS} = 0V$	—	-0.8	-1.2	V
Schottky Diode						
Forward Voltage Drop	V_F	$I_F = 0.5A$	—	0.42	0.48	V
Maximum Reverse Leakage Current	I_{rm}	$V_r = 20V$	—	0.002	0.1	mA
Junction Capacitance	C_T	$V_r = 10V$	—	35	—	pF

Typical characteristics (25°C unless noted)

MOSFET

Figure 1 Threshold Voltage vs. Temperature

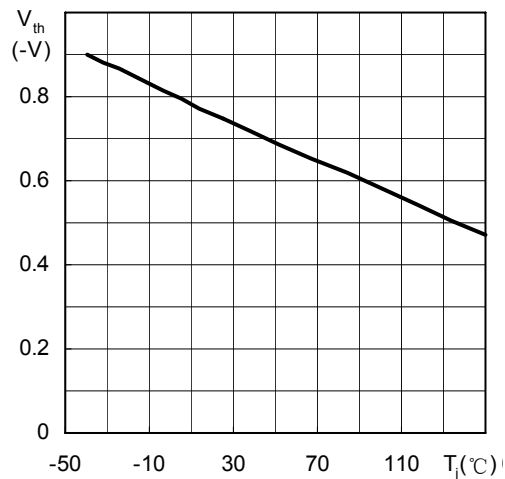
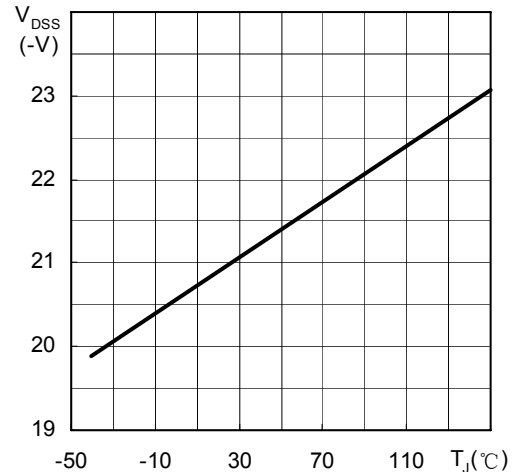
Figure 2 V_{DSS} vs. Temperature

Figure 3 I_{DSS} vs. Temperature

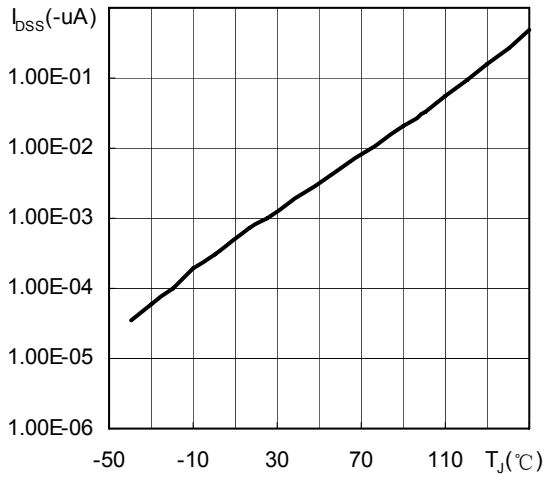


Figure 4 I_{GSS} vs. Temperature

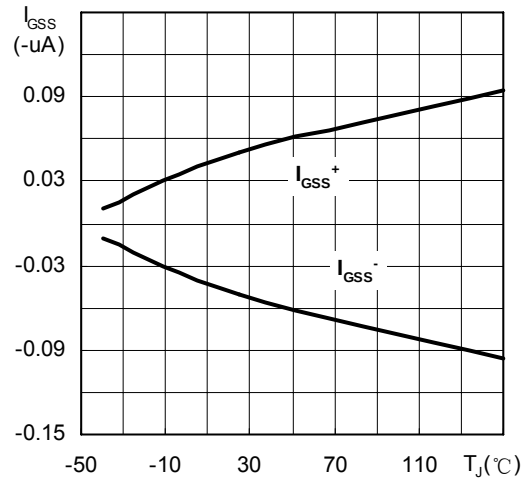


Figure 5 On-Resistance vs. Temperature

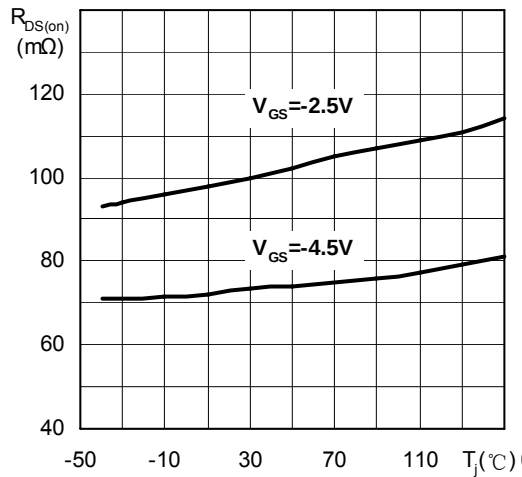


Figure 6 On-Resistance vs. Drain Current

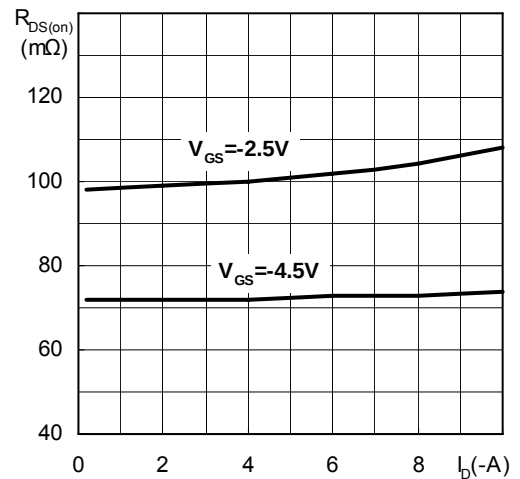


Figure 7 On-Resistance vs. Gate-to-Source Voltage

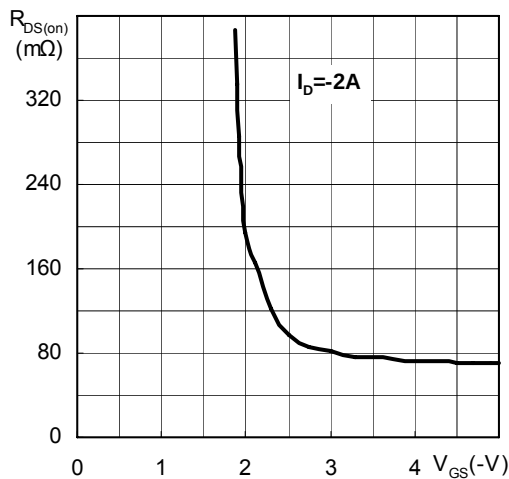


Figure 8 Drain to Source Voltage vs. Drain Current

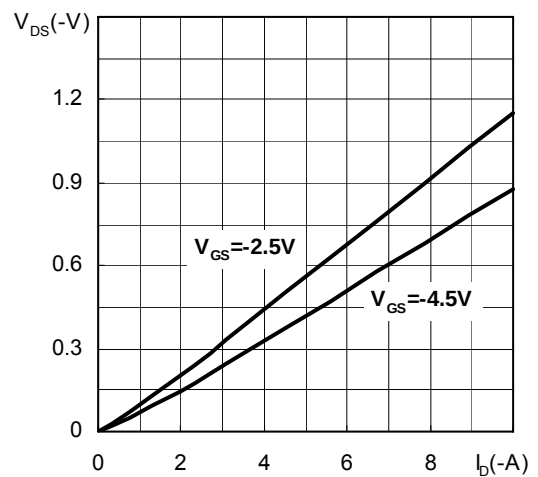


Figure 9 Gate Charge

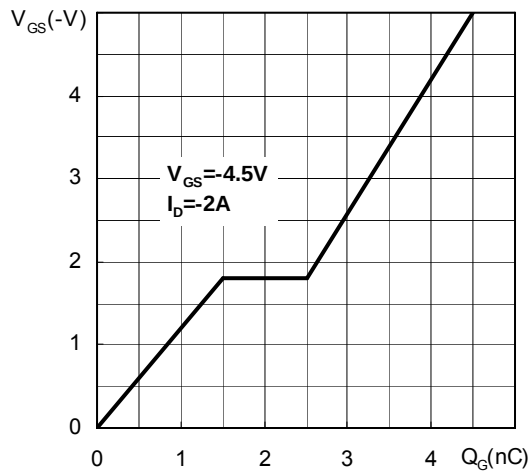
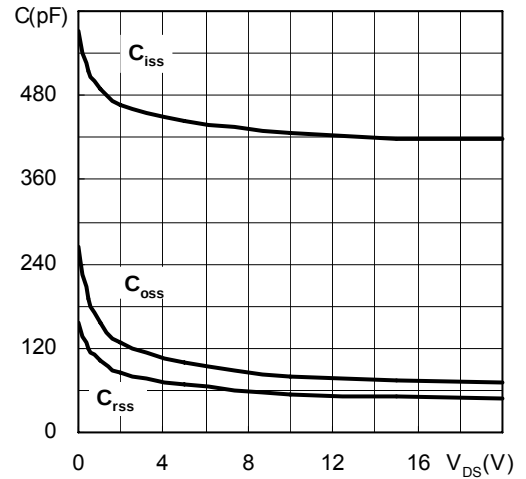


Figure 10 Capacitance



Typical characteristics (25°C unless noted)

Schottky Diode

Figure 11 Reverse Current vs. Junction Temperature

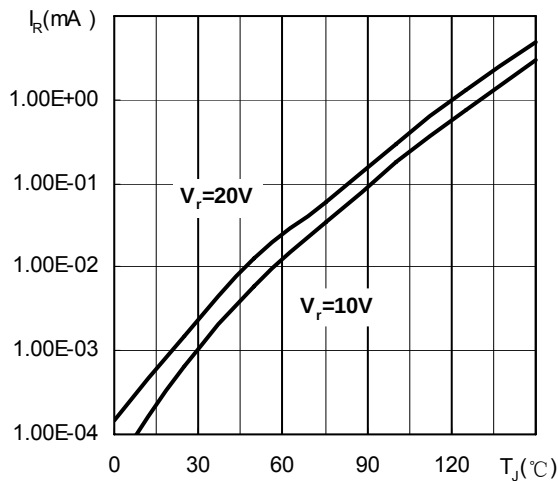


Figure 12 Forward Voltage Diode

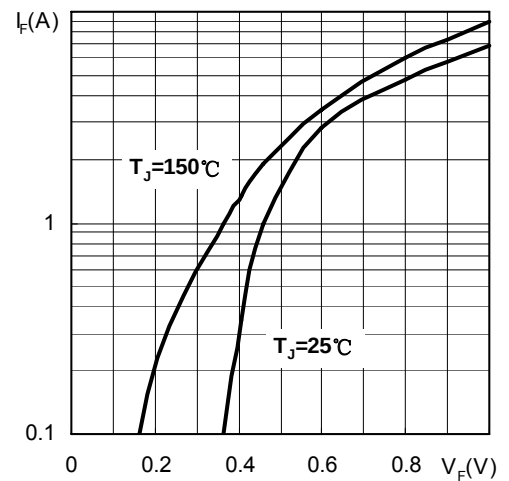
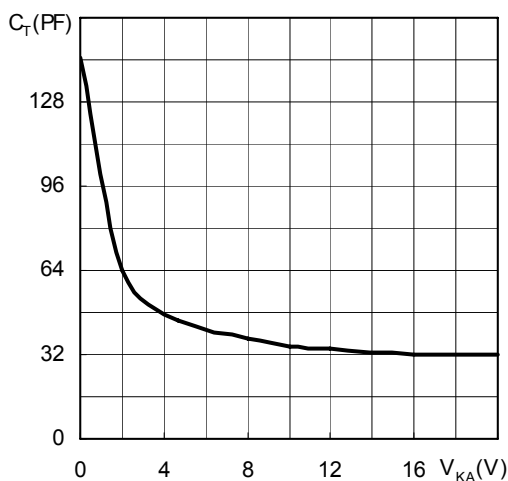
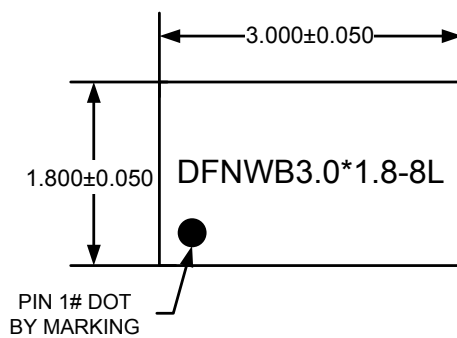


Figure 13 Capacitance

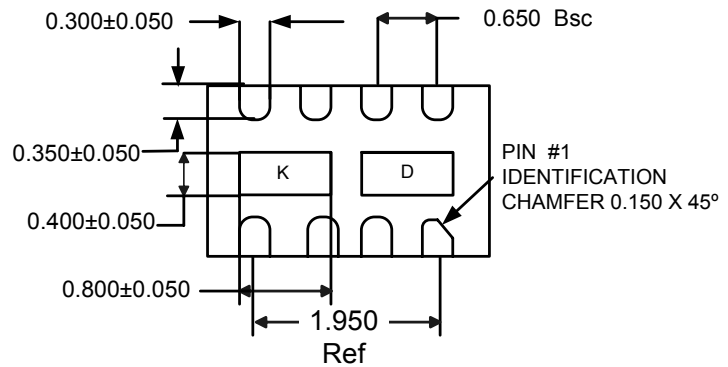




Package Drawing



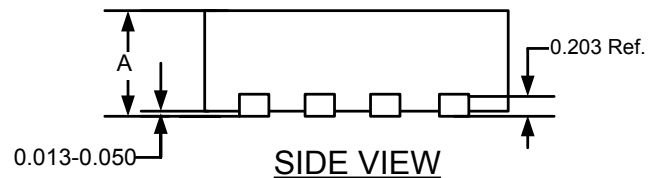
TOP VIEW



BOTTOM VIEW

UNIT:MM

A	MAX	0.800
	NDM	0.750
	MIN	0.700



SIDE VIEW

NOTE:

- 1) Lead Plating Thickness: 0-0.050mm.
- 2) Package body sizes exclude mold flash, protrusion or gate burrs.
Mold flash, protrusion or gate burrs shall not exceed 0.10mm per side.
- 3) The size of the zone "D" is the same as the "K".



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